

IEC QUALITY ASSESSMENT SYSTEM (IECQ) covering Electronic Components, Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L JQAJP 13.0002

CB Certificate No.: JQAQ0002-001-T

Schedule Number: IECQ-L JQAJP 13.0002-S Rev No.: 11 Revision Date: 2023/10/31 Page 1 of 2

TESTD PARTS

Fixed capacitor, Fixed resistor, Semiconductor Integrated Circuit

ENVIRONMENTAL TEST

IEC 60068-2-1:2007 Cold IEC 60068-2-2:2007 Dry heat

STRESS TEST

JEITA ED-4701/302A:2020 Environmental and endurance test methods for semiconductor devices (Stress test I-2) Test method 305D Charged device model electrostatic discharge (CDM/ESD)

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MEASUREMENT RANGE

Passive component		
Type / Part name	Measurable property value	Measuring range
Fixed capacitor	(1)Voltage endurance (DC)	: AC,DC 0 ~ 5kV
	(2)Insulation resistance	: $5 \times 10^5 \Omega \sim 10^{14} \Omega$
	(3)leakage current	: $1 \times 10^{-3} \sim 10 \text{ A}^{-11}$
	(4)Capacitance	$: 18 \mathrm{pF} \sim 1\mathrm{F}^*$
	(5)Dielectric loss tangent(D factor)	: 10 [*] min
	(6)Impedanc	$: 1\Omega \sim 10^* M\Omega$
	Attention : * The mark varies according to measurement frequency.	
Fixed resistor	(1)Resistance value	$:1\Omega \sim 100 M\Omega$
	(2)Insulation resistance	: $5 \times 10^5 \Omega \sim 2 \times 0^{14} \Omega$
	(3)Voltage endurance	: AC,DC 0 ~ 5kV
CMOS IC	(1)The high-level output voltage	:±30V
	(2)The low-level output voltage	:±30V
	(3)The high-level input voltage	:±20V
	(4)Low-level input electric current	:±20V
	(5)High-level output electric current	:±300mA
	(6)Low-level output electric current	:±300mA
	(7)Static consumption electric current	:±300mA
	(8)Input current	:±300mA

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